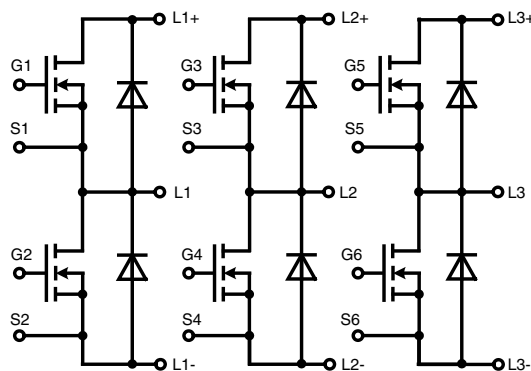
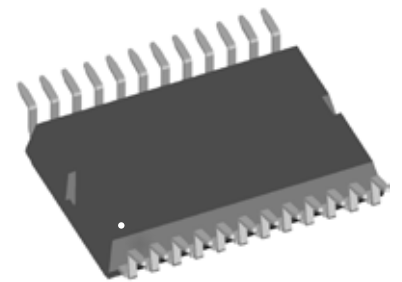


Three phase full Bridge
with Trench MOSFETs
in DCB-isolated high-current package

$V_{DSS} = 100\text{ V}$
 $I_{D25} = 190\text{ A}$
 $R_{DSon\ typ.} = 1.7\text{ m}\Omega$

Part number
MTI145WX100GD



Features / Advantages:

- MOSFETs in trench technology:
 - low R_{DSon}
 - optimized intrinsic reverse diode
- Package:
 - high level of integration
 - high current capability
 - aux. terminals for MOSFET control
 - terminals for soldering or welding connections
 - isolated DCB ceramic base plate with optimized heat transfer
- Space and weight savings

Applications:

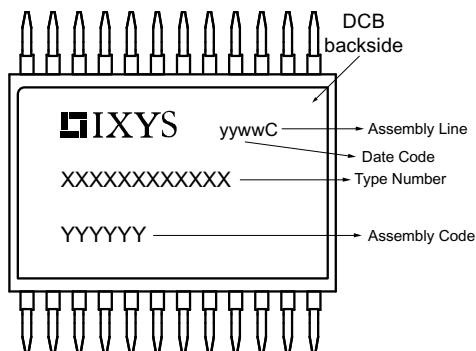
- AC drives
- in automobiles
 - electric power steering
 - starter generator
 - in industrial vehicles
 - propulsion drives
 - fork lift drives
 - in battery supplied equipment

Package: ISOPLUS-DIL®

- High level of integration
- RoHS compliant
- High current capability
- Aux. Terminals for MOSFET control
- Terminals for soldering or welding connections
- Space and weight savings

MOSFETs				Ratings			
Symbol	Definitions	Conditions	min.	typ.	max.	Unit	
V_{DSS}	drain source breakdown voltage	$T_{VJ} = 25^{\circ}\text{C to } 150^{\circ}\text{C}$			100	V	
V_{GS}	gate source voltage				± 15	V	
V_{GSM}	max. transient gate source voltage				± 20	V	
I_{D25}	continuous drain current	$T_C = 25^{\circ}\text{C}$			190	A	
I_{D90}		$T_C = 90^{\circ}\text{C}$			145	A	
$R_{DS(on)}^{1)}$	static drain source on resistance	on chip level at $I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$	$T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 125^{\circ}\text{C}$	1.7 2.9	2.2	m Ω m Ω	
$V_{GS(th)}$	gate threshold voltage	$I_D = 275 \mu\text{A}; V_{DS} = V_{GS}$	$T_{VJ} = 25^{\circ}\text{C}$	2.0	2.7	3.5	V
I_{DSS}	drain source leakage current	$V_{DS} = V_{DSS}; V_{GS} = 0 \text{ V}$	$T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 125^{\circ}\text{C}$		1 100	μA μA	
I_{GSS}	gate source leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$			500	nA	
R_G	gate resistance	on chip level		1.9		Ω	
C_{iss}	input capacitance	} $V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V}; f = 1 \text{ Mhz}$		11.1		nF	
C_{oss}	output capacitance			1.94		nF	
C_{rss}	reverse transfer capacitance			70		pF	
Q_g	total gate charge	} $V_{GS} = 10 \text{ V}; V_{DS} = 50 \text{ V}; I_D = 100 \text{ A}$		155		nC	
Q_{gs}	gate source charge			48		nC	
Q_{gd}	gate drain (Miller) charge			27		nC	
$t_{d(on)}$	turn-on delay time	} inductive load $V_{GS} = 10 \text{ V}; V_{DS} = 50 \text{ V}$ $I_D = 100 \text{ A}; R_G = 27 \Omega$	$T_{VJ} = 125^{\circ}\text{C}$		135	ns	
t_r	current rise time				75	ns	
$t_{d(off)}$	turn-off delay time				600	ns	
t_f	current fall time				40	ns	
E_{on}	turn-on energy per pulse				200	μJ	
E_{off}	turn-off energy per pulse				600	μJ	
$E_{rec(off)}$	turn-off reverse recovery losses		36	μJ			
R_{thJC}	thermal resistance junction to case				0.85	K/W	
R_{thJH}	thermal resistance junction to heatsink	with heat transfer paste (IXYS test setup)		1.1	1.4	K/W	
		$^1) V_{DS} = I_D \cdot (R_{DS(on)} + 2 \cdot R_{Pin \text{ to Chip}})$					
Source-Drain Diode							
I_{F25}	forward current		$T_C = 25^{\circ}\text{C}$		180	A	
I_{F90}			$T_C = 90^{\circ}\text{C}$		105	A	
V_{SD}	source drain voltage	$I_F = 100 \text{ A}; V_{GS} = 0 \text{ V}$	$T_{VJ} = 25^{\circ}\text{C}$	0.9	1.2	V	
Q_{RM}	reverse recovery charge	} $V_R = 50 \text{ V}; I_F = 100 \text{ A}$ $R_G = 27 \Omega$ (di/dt = 1700 A/ μs)	$T_{VJ} = 125^{\circ}\text{C}$		2	μC	
I_{RM}	max. reverse recovery current				54	A	
t_{rr}	reverse recovery time				60	ns	

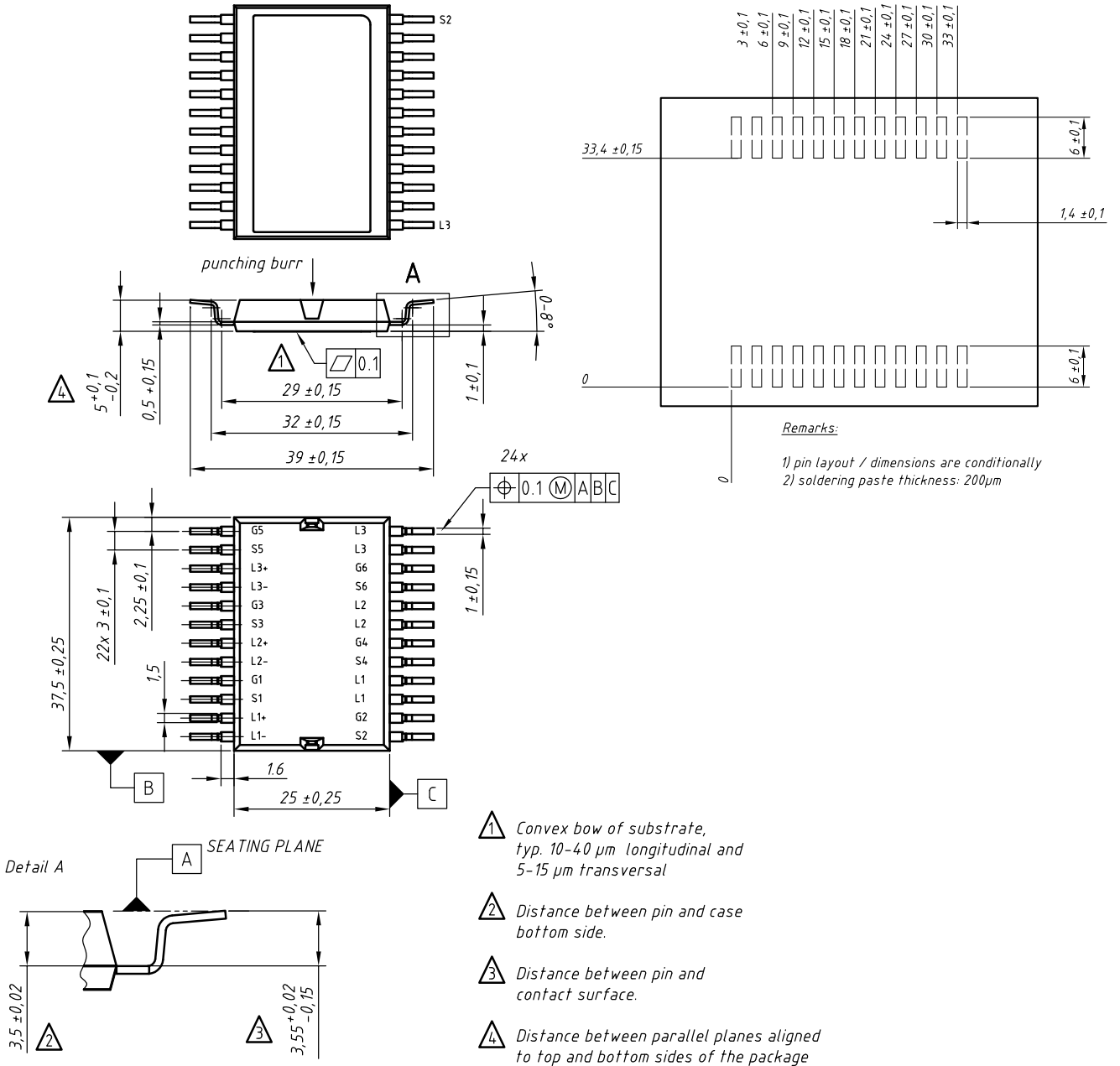
Package ISOPLUS-DIL®			Ratings			
Symbol	Definitions	Conditions	min.	typ.	max.	Unit
I_{RMS}	RMS current	per pin in main current paths (L1+...L3+, L1-...L3-, L1...L3) may be additionally limited by external connections (PCB tracks) 2 pins for output L1, L2, L3			75	A
T_{stg}	storage temperature		-55		125	°C
T_{VJM}	virtual junction temperature		-55		175	°C
Weight				25		g
F_C	mounting force with clip		50		250	N
V_{ISOL}	isolation voltage	$t = 1$ second	50/60 Hz, RMS, $I_{ISOL} \leq 1$ mA	1200		V
		$t = 1$ minute		1000		V
$R_{pin-chip}$	resistance terminal to chip	$V_{DS} = I_D \cdot (R_{DS(on)} + 2 \cdot R_{pin\ to\ chip})$		0.5		mΩ
C_P	coupling capacity	between shorted pins and back side metallization		160		pF


Part number

- M = Module
- T = Trench MOSFET
- I = OPTIMOS
- 145 = Current Rating [A]
- WX = 6-Pack with separated Phase Legs
- 100 = Reverse Voltage [V]
- GD = ISOPLUS-DIL

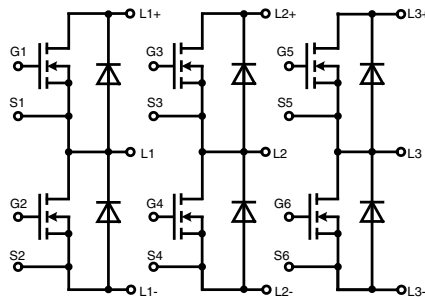
Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	MTI145WX100GD-SMD	MTI145WX100GD	Blister	28	513435

Outlines ISOPLUS-DIL®



contact pin:

- galv. tin plating, per pin side: Sn 10...25 µm, undercoating Ni 0,2...1 µm
- stamping edges may be free of tin
- punching burr: ≤ 0,05mm



IXYS reserves the right to change limits, test conditions and dimensions.

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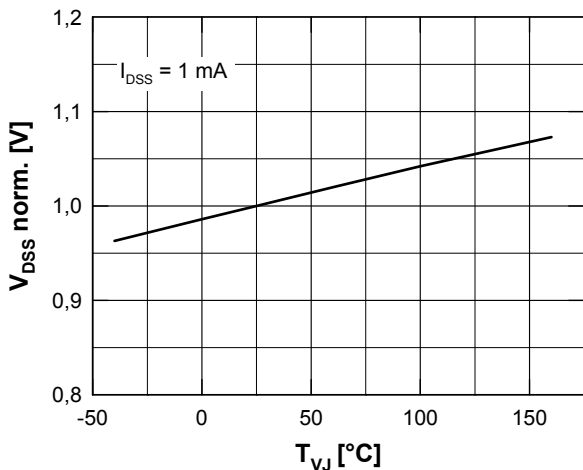


Fig. 1 Drain source breakdown voltage V_{DSS} vs. junction temperature T_{VJ}

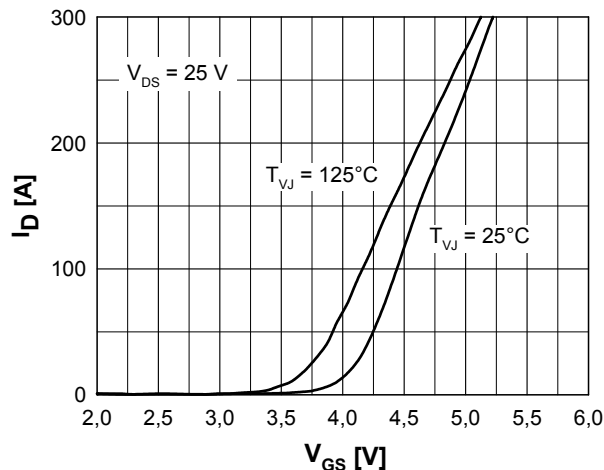


Fig. 2 Typ. transfer characteristics

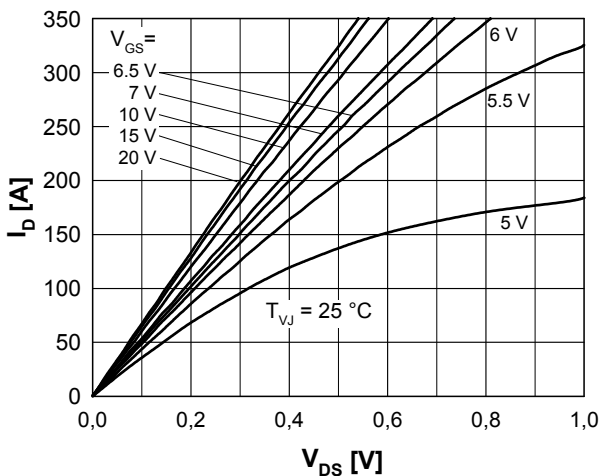


Fig. 3 Typ. output characteristics (25 °C)

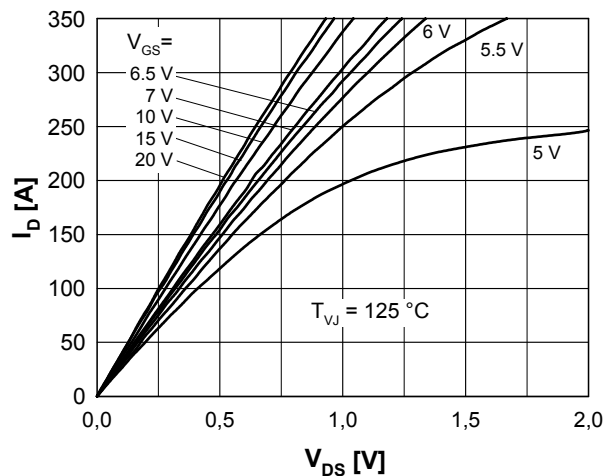


Fig. 4 Typ. output characteristics (125 °C)

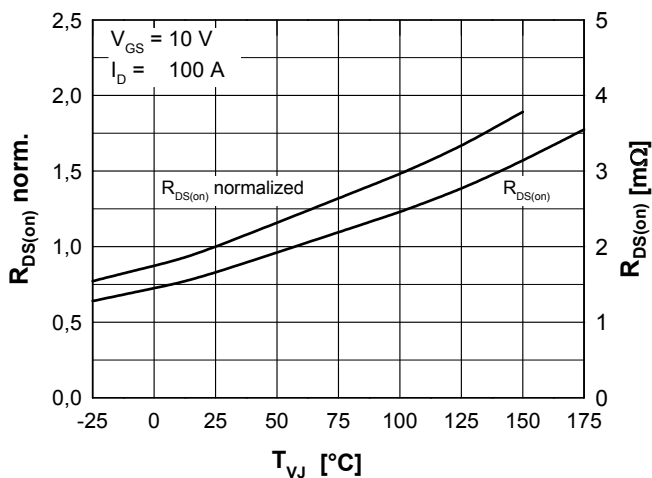


Fig. 5 Drain source on-state resistance versus junction temperature

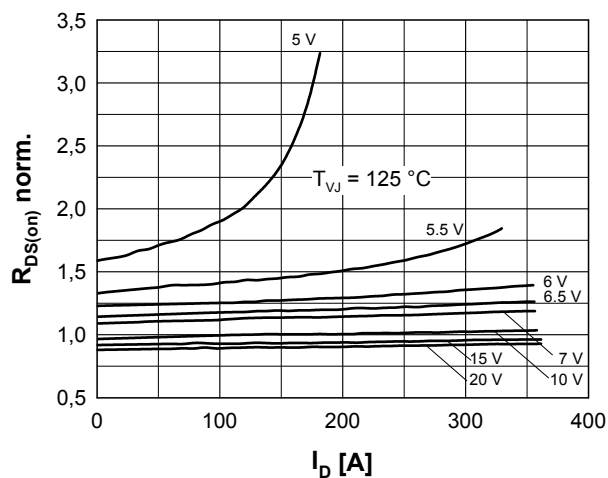


Fig. 6 Drain source on-state resistance versus I_D

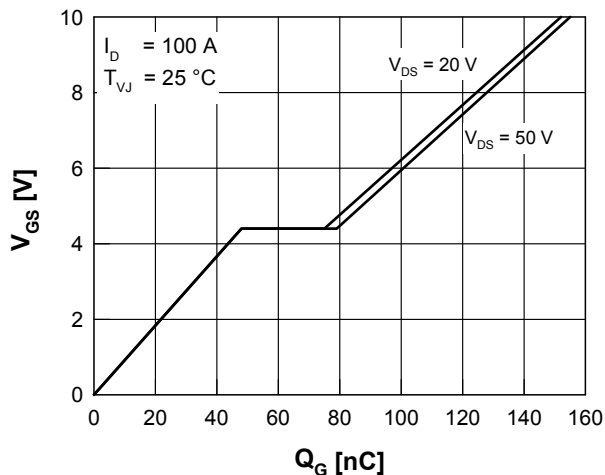


Fig. 7 Typical turn on gate charge

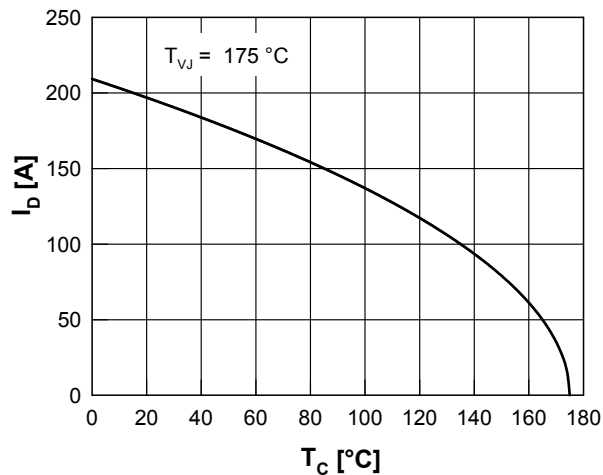
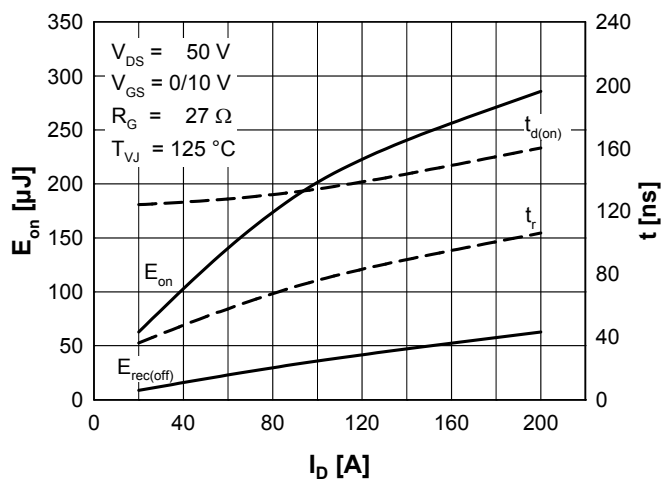

 Fig. 8 Drain current I_D vs. case temperature T_C (chip capability)


Fig. 9 Typ. turn-on energy and switching times versus drain current, inductive switching

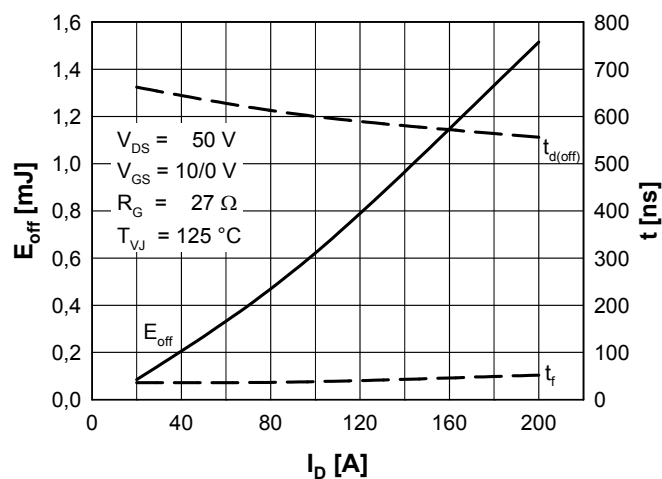


Fig. 10 Typ. turn-off energy and switching times versus drain-current, inductive switching

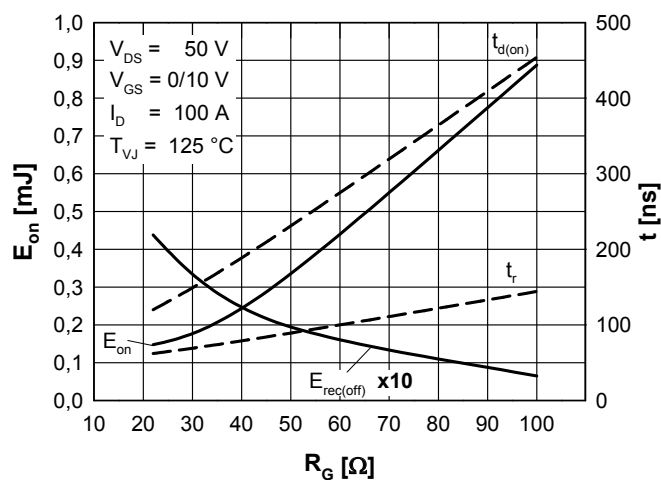


Fig. 11 Typ. turn-on energy and switching times versus gate resistor, inductive switching

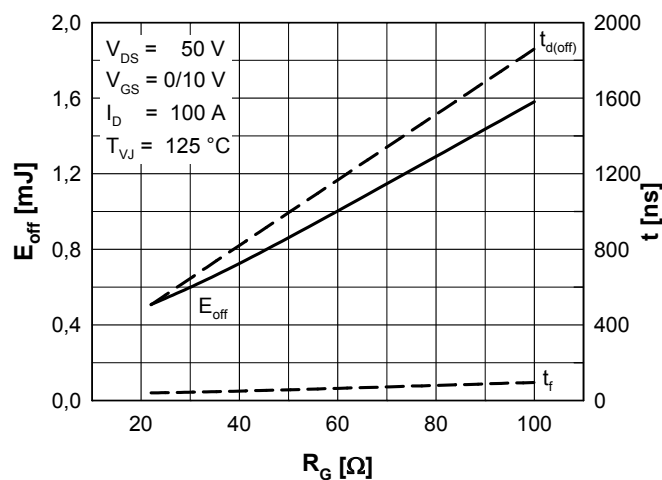


Fig. 12 Typ. turn-off energy and switching times versus gate resistor, inductive switching

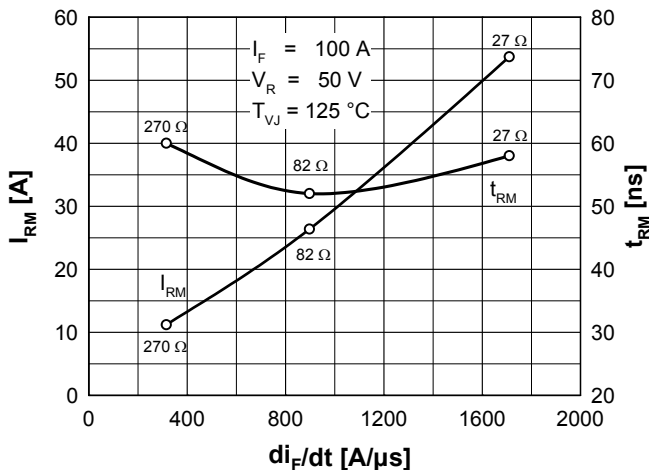


Fig. 13 Reverse recovery time t_{RM} of the body diode vs. di_F/dt

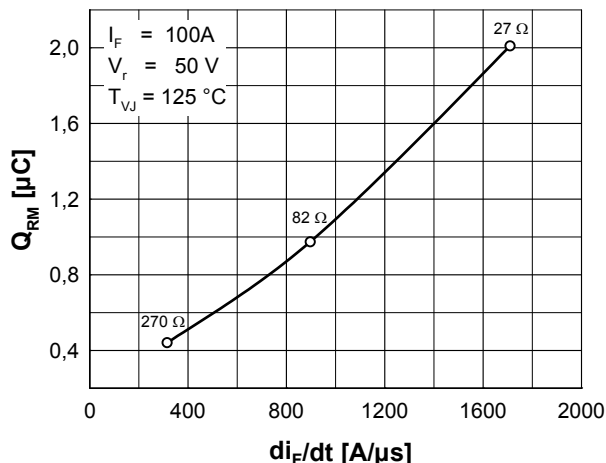


Fig. 14 Reverse recovery charge Q_{RM} of the body diode vs. di_F/dt

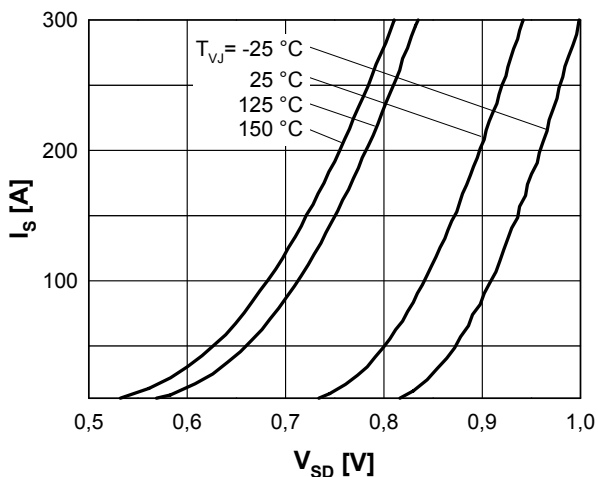


Fig.15 Source current I_S vs. source drain voltage V_{SD} (body diode)

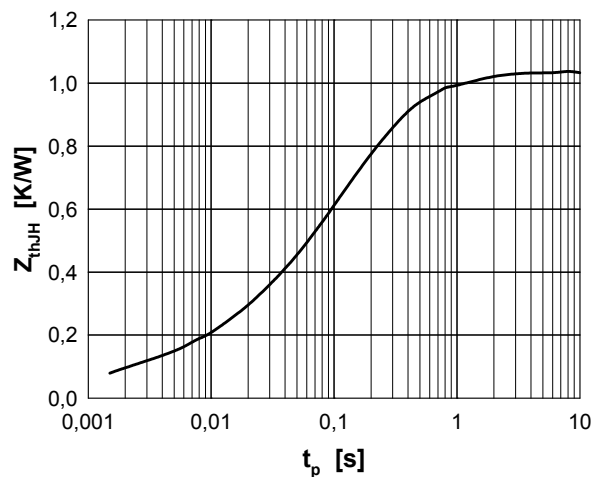


Fig. 16 Typ. thermal impedance junction to heatsink Z_{thJH} with heat transfer paste (IXYS test setup)

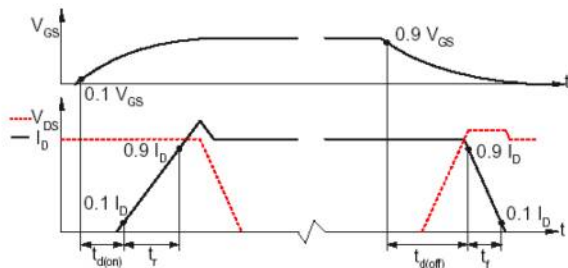


Fig. 17 Definition of switching times